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(54) Title: A HIGH PERFORMANCE SERIAL BUS TESTING METHODOLOGY

(57) Abstract: According to one embodiment, a built-in self test (IBIST) architecture/methodology is disclosed. The IBIST provides for testing the functionality of an interconnect (such as a bus) between a transmitter and a receiver component. The IBIST architecture includes a pattern generator and a pattern checker. The pattern checker operates to compare a received plurality of bits (for the pattern generator) with a previously stored plurality of bits.

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